RF LDMOS Wideband Integrated **Power Amplifier**

The MHVIC2115R2 wideband integrated circuit is designed for base station applications. It uses Freescale's newest High Voltage (26 to 28 Volts) LDMOS IC technology and integrates a multi-stage structure. Its wideband On-Chip matching design makes it usable from 1600 to 2600 MHz. The linearity performances cover W-CDMA modulation formats.

Final Application

 Typical W-CDMA Performance: -45 dBc ACPR, 2110-2170 MHz, V_{DD} = 27 Volts, $I_{DQ1} = 56$ mA, $I_{DQ2} = 61$ mA, $I_{DQ3} = 117$ mA, $P_{out} = 34$ dBm, 3GPP Test Model 1, Measured in a 1.0 MHz BW @ 4 MHz offset, 64 DTCH Power Gain - 30 dB PAE = 16%

Driver Application

- Typical W-CDMA Performance: -53 dBc ACPR, 2110-2170 MHz, V_{DD} = 26 Volts, I_{DQ1} = 96 mA, I_{DQ2} = 204 mA, I_{DQ3} = 111 mA, P_{out} = 23 dBm, 3GPP Test Model 1, Measured in a 3.84 MHz BW @ 5 MHz offset, 64 DTCH Power Gain — 34 dB
- Gain Flatness = 0.3 dB from 2110-2170 MHz
- P1dB = 15 Watts, Gain Flatness = 0.2 dB from 2110-2170 MHz
- Capable of Handling 3:1 VSWR, @ 26 Vdc, 2140 MHz, 15 Watts CW Output Power
- Characterized with Series Equivalent Large-Signal Impedance Parameters
- On-Chip Matching (50 Ohm Input, DC Blocked, >5 Ohm Output)
- Integrated Temperature Compensation with Enable/Disable Function
- Integrated ESD Protection
- In Tape and Reel. R2 Suffix = 1,500 Units per 16 mm, 13 inch Reel.

MHVIC2115R2

2170 MHz, 26 V, 23/34 dBm W-CDMA **RF LDMOS WIDEBAND** INTEGRATED POWER AMPLIFIER

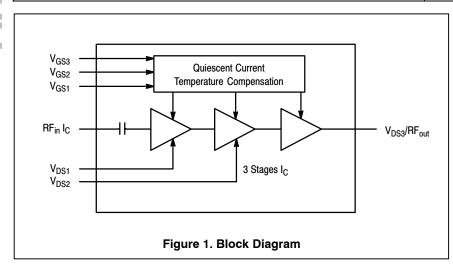


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Replaced by MHVIC2115NR2. There are no form, fit or function changes with this part replacement. N suffix indicates RoHS compliant part.

Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	-0.5, +65	Vdc
Gate-Source Voltage	V _{GS}	-0.5, +15	Vdc
Storage Temperature Range	T _{stg}	- 65 to +150	°C
Operating Junction Temperature	TJ	150	°C



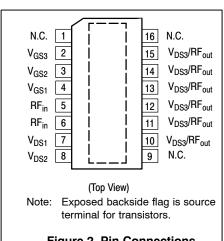


Figure 2. Pin Connections





Table 2. Thermal Characteristics

Characteristic		Symbol	Value	Unit
Thermal Resistance, Junction to	Case	$R_{ heta JC}$		°C/W
Driver Application (P _{out} = +0.2 W CW)	Stage 1, 26 Vdc, I_{DQ} = 96 mA Stage 2, 26 Vdc, I_{DQ} = 204 mA Stage 3, 26 Vdc, I_{DQ} = 111 mA		3.5	
Output Application (P _{out} = +2.5 W CW)	Stage 1, 27 Vdc, I_{DQ} = 56 mA Stage 2, 27 Vdc, I_{DQ} = 61 mA Stage 3, 27 Vdc, I_{DQ} = 117 mA		2.7	

Table 3. ESD Protection Characteristics

Test Conditions	Class
Human Body Model	1 (Minimum)
Machine Model	M1 (Minimum)
Charge Device Model	C2 (Minimum)

Table 4. Moisture Sensitivity Level

Test Methodology	Rating	Package Peak Temperature	Unit	
Per JESD 22-A113, IPC/JEDEC J-STD-020	3	240	°C	ĺ

Table 5. Electrical Characteristics ($T_C = 25^{\circ}C$ unless otherwise noted)

Characteristic	Symbol	MIN	тур	wax	Unit
W-CDMA Characteristics (In Freescale Test Fixture, 50 ohm syste $P_{out} = 23 \text{ dBm}$, 2110-2170 MHz	em) V _{DD} = 26 Vo	dc, I _{DQ1} = 96	mA, I _{DQ2} = 204 n	nA, I _{DQ3} = 111	mA,

Power Gain	G _{ps}	31	34	_	dB
Gain Flatness	G _F	_	0.3	0.5	dB
Input Return Loss	IRL	_	-12	-10	dB
Group Delay	_	_	1.7	_	ns
Phase Linearity	_	_	0.2	_	٥
1-Carrier W-CDMA Conditions: Adjacent Channel Power Ratio @ Pout = 23 dBm, 5 MHz Offset	ACPR	_	-53	-50	dBc
1 - Carrier W - CDMA Conditions: Adjacent Channel Power Ratio @ P _{out} = 28 dBm, 5 MHz Offset	ACPR	_	-50	_	dBc

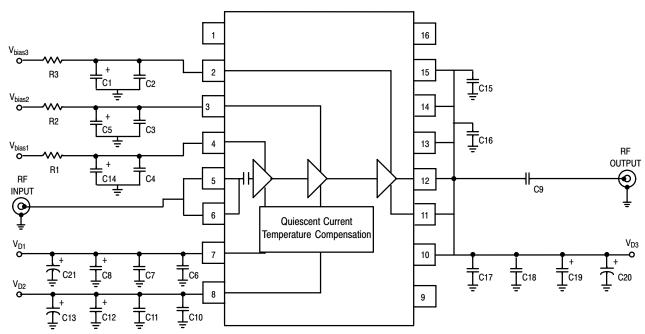
 $\textbf{W-CDMA Characteristics} \text{ (In Freescale Test Fixture, 50 ohm system) } V_{DD} = 27 \text{ Vdc}, I_{DQ1} = 56 \text{ mA}, I_{DQ2} = 61 \text{ mA}, I_{DQ3} = 117 \text{ mA}, P_{out} = 34 \text{ dBm}, 2110-2170 \text{ MHz}$

, , , , , , , , , , , , , , , , , , ,					
Power Gain	G _{ps}	_	30	_	dB
Gain Flatness	G _F	_	0.2	_	dB
Input Return Loss	IRL	_	-12	_	dB
Power Added Efficiency	PAE	_	16	_	%
1 - Carrier W - CDMA Conditions: Adjacent Channel Power Ratio @ P _{out} = 34 dBm, 4 MHz Offset	ACPR	_	-45	_	dBc

NOTE - **CAUTION** - MOS devices are susceptible to damage from electrostatic charge. Reasonable precautions in handling and packaging MOS devices should be observed.



ARCHIVE INFORMATION



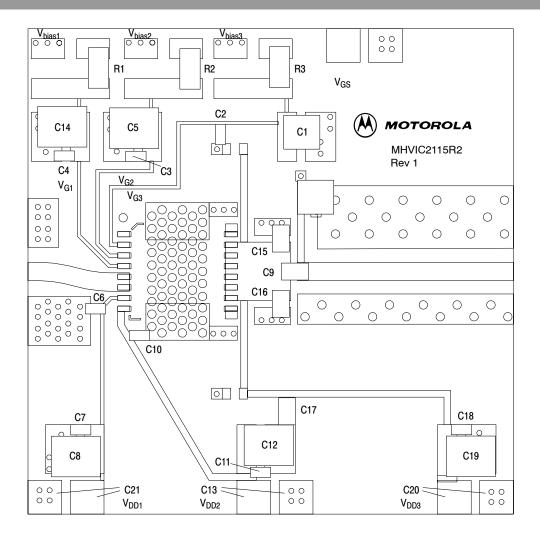
C2, C3, C4, C7, C11, C18 C6, C10, C17 C9, C15, C16

C1, C5, C8, C12, C14, C19 1 mF SMT Tantalum Chip Capacitors 0.01 mF Chip Capacitors (0805C103K5RACTR) 6.8 pF Chip Capacitors, ACCU-P (AVX 08051J6R8BBT) 1.8 pF Chip Capacitors, ACCU-P (AVX 08051J1R8BBT)

C13, C20, C21 330 mF Electrolytic Capacitors (MCR35V337M10X16) R1, R2, R3 1 kW Chip Resistors (0805) **PCB** Arlon, 0.020,, $e_r = 2.55$

Figure 3. MHVIC2115R2 Demo Board Schematic





Freescale has begun the transition of marking Printed Circuit Boards (PCBs) with the Freescale Semiconductor signature/logo. PCBs may have either Motorola or Freescale markings during the transition period. These changes will have no impact on form, fit or function of the current product.

Figure 4. MHVIC2115R2 Demo Board Component Layout



TYPICAL CHARACTERISTICS

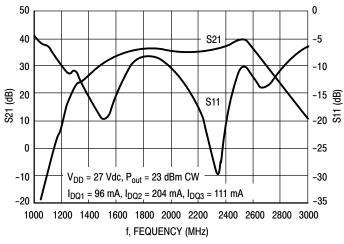


Figure 5. Broadband Frequency Response

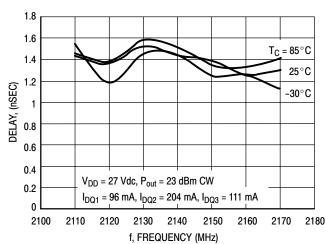


Figure 6. Delay versus Frequency

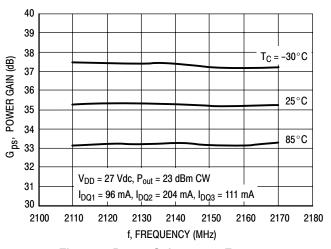


Figure 7. Power Gain versus Frequency

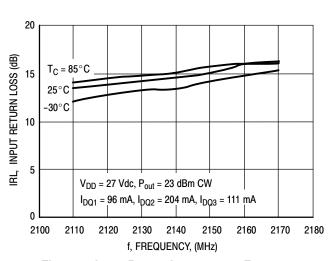


Figure 8. Input Return Loss versus Frequency

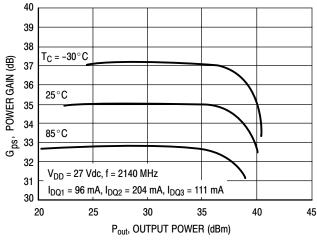


Figure 9. Power Gain versus Output Power

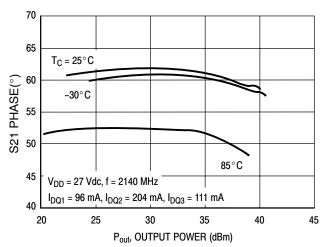


Figure 10. S21 Phase versus Output Power

MHVIC2115R2



TYPICAL CHARACTERISTICS

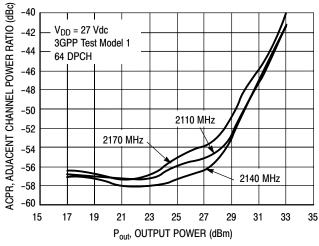


Figure 11. W-CDMA ACPR versus Output Power

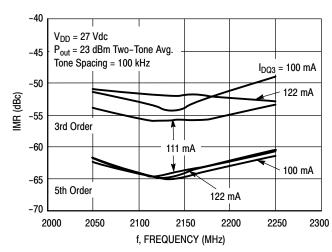


Figure 12. Two-Tone IMR versus Frequency

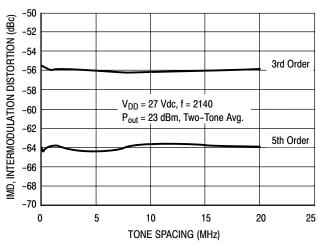


Figure 13. Two-Tone Broadband Performance

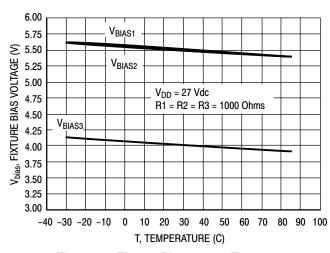


Figure 14. Fixture Bias versus Temperature

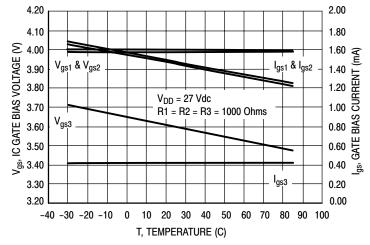
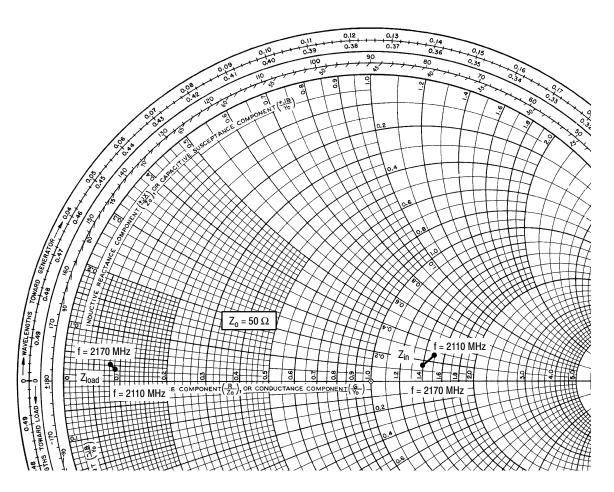


Figure 15. Gate Bias versus Temperature





 $V_{DD} = 27 \text{ Vdc}, I_{DQ} = 1411 \text{ mA}, P_{out} = 15 \text{ W Avg}.$

f MHz	Z _{in} Ω	$oldsymbol{Z_{load}}{\Omega}$
2110	72.55 + j12.8	4.25 + j1.00
2140	71.40 + j9.9	4.13 + j1.37
2170	70.20 + j7.1	4.12 + j1.46

 $Z_{in} \qquad \qquad \text{Device input impedance as measured from} \\ \text{gate to ground}.$

 Z_{load} = Test circuit impedance as measured from drain to ground.

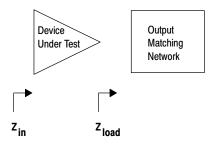
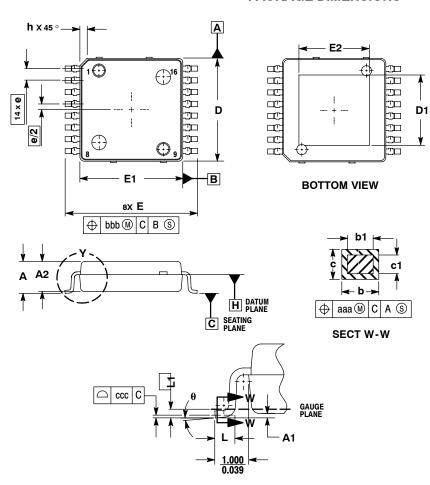


Figure 16. Series Equivalent Input and Load Impedance



PACKAGE DIMENSIONS



DETAIL Y

CASE 978-03 ISSUE C PFP-16

NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
 2. DIMENSIONS AND TOLERANCES PER ASME

- 2. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
 3. DATUM PLANE -H- IS LOCATED AT BOTTOM OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE BOTTOM OF THE PARTING LINE.
 4. DIMENSIONS D AND E1 DD NOT INCLUDE MOLD PROTRUSION, ALLOWABLE PROTRUSION IS 0.250 PER SIDE. DIMENSIONS D AND E1 DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATILIN PI AND. -H
 DETERMINED AT DATILIN PI AND. -H-
- DETERMINED AT DATUM PLANE -H-.
 5. DIMENSION & DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION IS 0.127 TOTAL IN EXCESS OF THE **b DIMENSION AT MAXIMUM MATERIAL** CONDITION.
- 6. DATUMS -A- AND -B- TO BE DETERMINED AT DATUM PLANE -H-.

	MILLIMETERS			
DIM	MIN MAX			
Α	2.000	2.300		
A1	0.025	0.100		
A2	1.950	2.100		
D	6.950	7.100		
D1	4.372	5.180		
E	8.850	9.150		
E1	6.950	7.100		
E2	4.372	5.180		
L	0.466	0.720		
L1	0.250 BSC			
b	0.300	0.432		
b1	0.300	0.375		
С	0.180	0.279		
c1	0.180	0.230		
е	0.800	BSC		
h		0.600		
θ	0°	7°		
aaa	0.2	200		
bbb	0.2	200		
CCC	0.100			



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Document Number: MHVIC2115R2

Rev. 4, 8/2006